

PATENT

Docket No. 29273/559

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of : Y. IWABUCHI et al.
Serial No. : (Cont. of 09/883,184)
Filed : February 27, 2002
For : METHOD AND APPARATUS OF AN INSPECTION
SYSTEM USING AN ELECTRON BEAM
Group Art Unit : 2881 (Anticipated)
Examiner : J. Berman (Anticipated)

ASSISTANT COMMISSIONER
FOR PATENTS
Washington, DC 20231

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98

S I R:

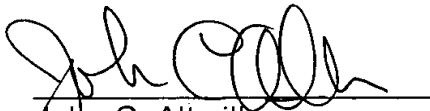
In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all of the references have already been considered in parent application number 09/883,184, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

Dated: 27 February 2002


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**FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)**

Atty Docket No.: 29273/559
Serial No. : TO BE ASSIGNED
Inventors : Y. IWABUCHI et al.
Filed : 27 February 2002
Group Art Unit: 2881 (Anticipated)
Examiner : J. Berman (Anticipated)



U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
<i>JP</i>	5,578,821	11/26/96	MEISBERGER et al.	250/310	
<i>JP</i>	5,502,306	03/26/96	MEISBERGER et al.	250/310	
<i>JP</i>	5,214,284	03/25/93	TOKUNAGA et al.	250/309	
<i>JP</i>	5,146,089	09/08/92	ROSIEN	250/309	
<i>JP</i>	4,713,543	12/1987	FEUERBAUM et al.	250/310	
<i>JP</i>	4,714,833	12/1987	ROSE et al.	250/310	
<i>JP</i>	5,872,358	02/1999	TODOKORO et al.	250/397	
<i>JP</i>	5,276,325	01/01/94	TODOKORO et al.	250/310	
<i>JP</i>	5,401,974	03/28/95	OAE et al.	250/492.2	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
<i>JP</i>	7-306028	11/21/95	Japan		ABS.
<i>JP</i>	7-286842	10/31/95	Japan		ABS.
<i>JP</i>	5-251525	09/28/93	Japan		ABS.
<i>JP</i>	4-297051	10/21/92	Japan		ABS.
<i>JP</i>	2-189848	07/25/90	Japan		ABS.

EXAMINER

DATE CONSIDERED

Jack Berman

5/30/02

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.